

Interference Search History Printout

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S161	0	((built-in-self-test (built-in adj self-test) BIST ("first logic" adj (module section circuit device))) and (interface JTAG "boundary scan" ("second logic" adj (modulesection circuit device))) and (((("third logic" adj (module section circuit device)) multiplex\$3 switch\$3) with (select\$5 near3 (connect\$3 coupl\$3))) with ((two plurality several multiple) near2 (control near2 signal))) and (\$2RAM memory SUT DUT CUT ((device chip circuit system) adj under adj test))).clm.	US-PGPUB	OR	ON	2008/04/11 14:49

Claims
22 1, 10, 13 and

4/ 11/ 2008 4:07:04 PM

C:\Documents and Settings\jtabone\My Documents\EAST\Workspaces\09933468.wsp